

AMENDMENTS

In the Claims

Please amend claim 1 as follows:

1. (Twice Amended) An integrated circuit probe card inspection system for probes in a probe array, comprising:

 a viewing system for providing a digital image of the tip of each probe,
 a window with a flat surface contacted by each of said probe tips, said viewing system obtaining said digital image of each probe tip through said window,
and

 a computer means with software means to determine and analyze the position of each probe within the digital image, said computer means with software means comprising:

 positioning means to determine the position of each probe in the digital image relative to a known physical position in order to determine the location of the probes relative to each other, and

means for mathematically moving the positions of the probes as determined by the positioning means relative to a predefined set of pad location data representative of locations of integrated circuit pads which are to be contacted by the probes to obtain a best fit therebetween, and identifying based on the best fit a minimum number of the probes which need to be adjusted with respect to position in order to align all of the probes with the respective integrated circuit pads
[automated means for evaluating a characteristic of at least one bus probe included in said probe array based on said relative location information].

REMARKS

Claims 1-11 are pending in this application. Claims 1-5 and 8-10 are presently under consideration. Favorable consideration of the application, as amended, is respectfully requested.

Claim 1 has been amended herein to clarify further the various features of the invention. In particular, claim 1 has been amended to recite means for